


<b>Search Notes</b>  	<b>Application/Control No.</b>  10811071	<b>Applicant(s)/Patent Under Reexamination</b>  FENNEY ET AL.
	<b>Examiner</b>  Hajnik, Daniel F	<b>Art Unit</b>  2628

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Update Search conducted in EAST	10/12/08	DFH
EAST text search (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB -- see search history printout)	10/12/08	DFH
Update search conducted in EAST	7/29/09	DFH
NPL search conducted in ACM, IEEE, and Google, search terms include sample, micropolygon, and primitive	7/30/09	DFH
EAST search history attached	8/1/09	DFH

INTERFERENCE SEARCH			
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